GEM test in Hall A

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SoLid GEM and SBS GEM



SoLid GEM(prototype)



SBS GEM(60x50 cm)

- Different in size and style of readout plane
- Share same structure
- High occupancy





Hit Reconstruction

2D Hit Map of all clusters



Y Plane(m

(mm) 2000 700 Y

2D hit Map

500 600 X Position (mm)

All possible cluster combination

Clusters recognized by tracking

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After tracking, add a rough cut in charge correlation and timing correlation

[≥] 9000 [⊨] ×8000 € e 7000 0009 Char

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Charge Correlation



1000 2000 3000 4000 5000 6000 7000 8000 9000 10000



Tracking Snapshots



Tracking Snapshots



Charge Correlation

Charge Correlation



0<u>⊢</u> 6000 7000 8000 9000 10000 Total Charge in X (adc value) 3000 4000

Charge Correlation

Charge Correlation

Charge Correlation





Timing Correlation



Local Efficiency at 4100V



Experience and Suggestion to SoLid GEMs

- Expereince of Hall A GEM test and previous X-ray test:
 - at low occupancy, tracking can remove most of accidentals and cross-talk signals
 - at high occupancy, charge correlation and timing cut will play a much more important role
 - Suggestion:
 - Better design of HV divider, for efficient HV supply to GEM at high occupancy.
 - Avoid using 1 time sample in case SoLid GEMs adopt APV25 chip.